

**Search Notes**

Application/Control No.

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Examiner

Chuck Huynh

Applicant(s)/Patent under  
Reexamination

CHOI ET AL.

Art Unit

2617

**SEARCHED**

Class	Subclass	Date	Examiner
Updated	Search	3/29/2006	CH
455	411	3/29/2006	CH

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Look over references	3/29/2006	CH